

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/682,224	<b>Applicant(s)/Patent under Reexamination</b> KIKUCHI ET AL.
<b>Examiner</b> Anthony Weier	<b>Art Unit</b> 1761	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
426	634, 518		
	486, 507	7/16/2006	AW